Appendix A

Detailed System Check Results

1. System Performance Check
System Performance Check 750 MHz Head
System Performance Check 1750 MHz Head
System Performance Check 1950 MHz Head

Measurement Report for Device, EDGE TOP, D750, CW, Channel 50 (750.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	10.0 x 10.0 x 10.0	1160	Dipole

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	EDGE TOP, 15.00	D750	CW, 0--	750.000, 50	9.08	0.885	42.7

Hardware Setup

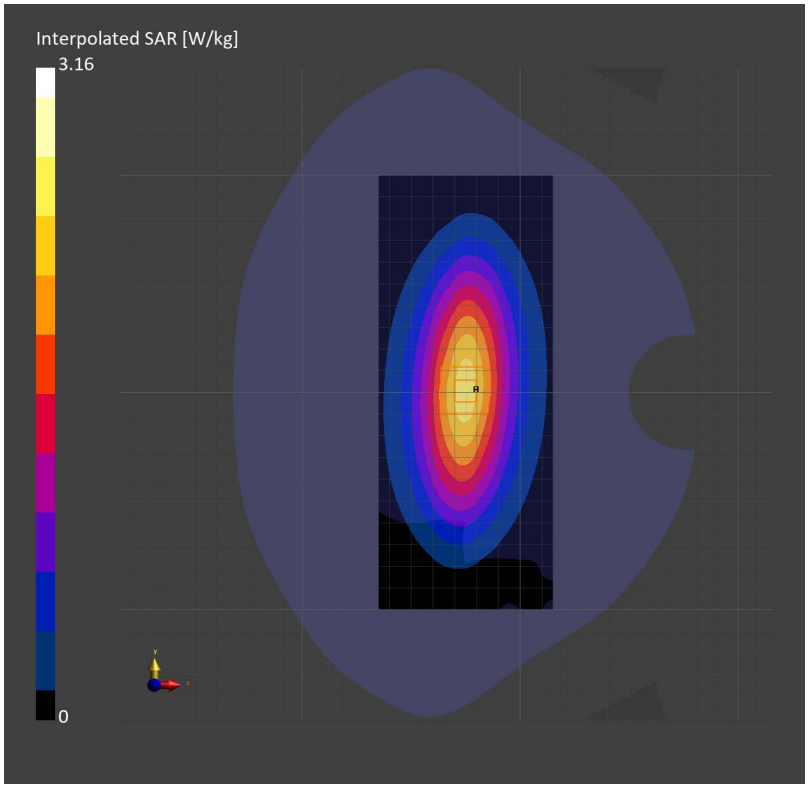
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2146	HBBL-600-10000 Charge:2023-08-27	EX3DV4 - SN7821, 2023-07-17	DAE4ip Sn1803, 2023-07-14

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	80.0 x 200.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2023-08-27	2023-08-27
psSAR1g [W/Kg]	2.21	2.20
psSAR10g [W/Kg]	1.47	1.48
Power Drift [dB]	-0.00	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction



Measurement Report for Device, EDGE TOP, D1750, CW, Channel 50 (1750.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	10.0 x 10.0 x 10.0	1149	Dipole

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	EDGE TOP, 10.00	D1750	CW, 0--	1750.000, 50	7.54	1.39	40.5

Hardware Setup

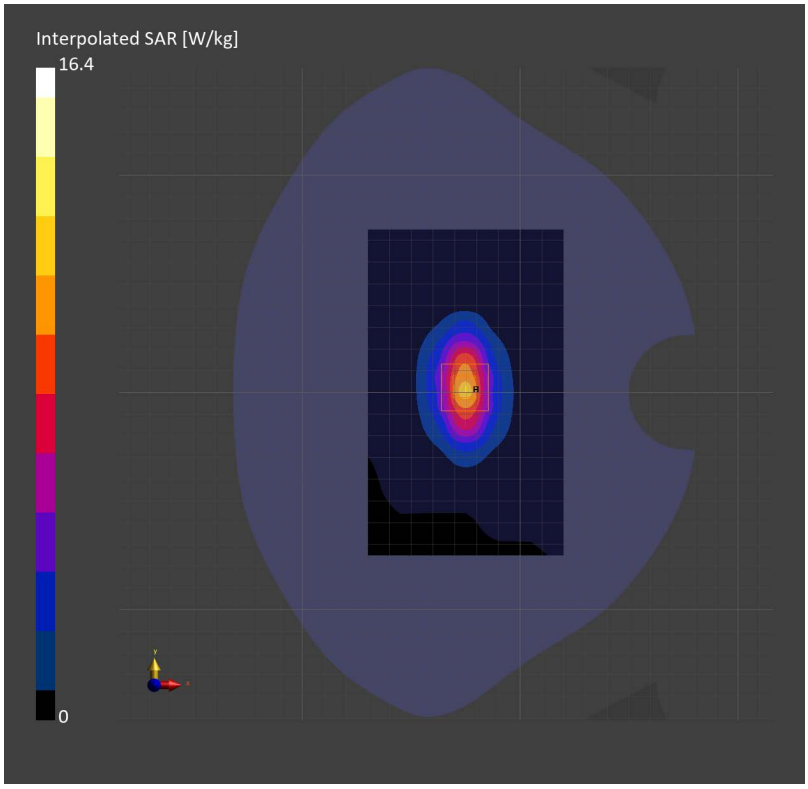
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2146	HBBL-600-10000 Charge:2023-08-27	EX3DV4 - SN7821, 2023-07-17	DAE4ip Sn1803, 2023-07-14

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 150.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2023-08-27	2023-08-27
psSAR1g [W/Kg]	9.19	9.26
psSAR10g [W/Kg]	4.89	5.00
Power Drift [dB]	0.00	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction



Measurement Report for Device, EDGE TOP, D1950, CW, Channel 50 (1950.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	10.0 x 10.0 x 10.0	1138	Dipole

Exposure Conditions

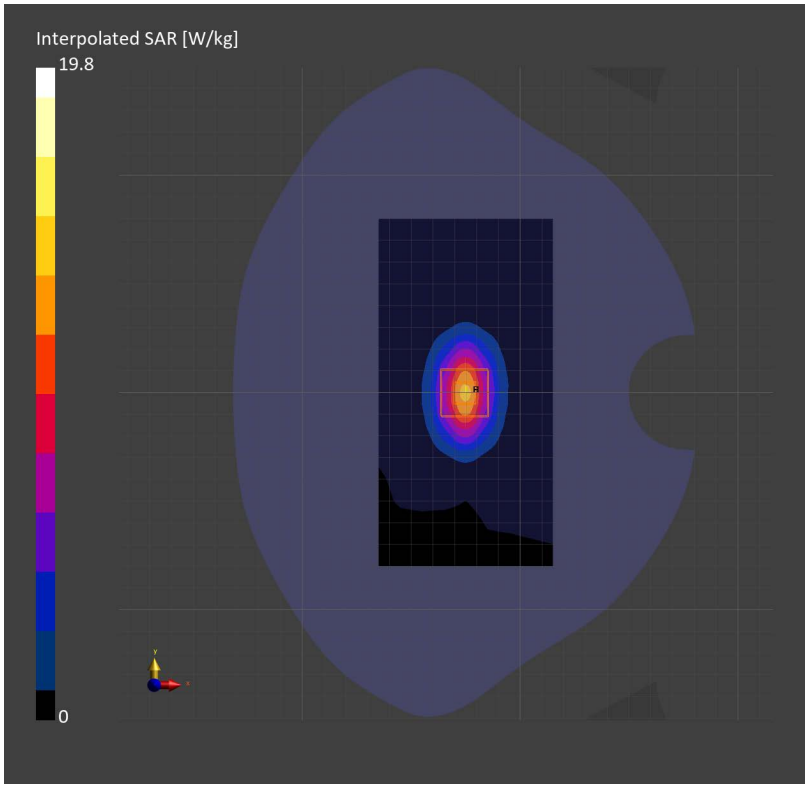
Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	EDGE TOP, 10.00	D1950	CW, 0--	1950.000, 50	7.35	1.43	40.2

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2146	HBBL-600-10000 Charge:2023-08-27	EX3DV4 - SN7821, 2023-07-17	DAE4ip Sn1803, 2023-07-14

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	80.0 x 160.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2023-08-27	2023-08-27
psSAR1g [W/Kg]	10.9	10.9
psSAR10g [W/Kg]	5.58	5.67
Power Drift [dB]	0.01	-0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction